



ABSTRACT

An automatic handler for an IC test system is disclosed which is capable of reducing a time for transferring IC devices to be tested from a supply area to a test head area and from the test head area to a discharge area. The automatic handler includes a test tray for loading the IC devices to be tested in which the IC devices to be tested are aligned in the test tray with a shorter distance with one another than a distance between test contactors in the test head area, a pair of positioning stoppers provided in the test head area along a moving direction of the test tray in which the positioning stoppers are spaced by the distance equal to the distance of the IC devices to be tested in the test tray. In the automatic handler, the distance of the contactors is adjusted to an integer multiple of the distance of the IC devices to be tested in the test tray. One of the positioning stoppers contacts the test tray to determine a first position for testing the IC devices in a first line in the test tray, and then the test tray is transferred until other positioning stoppers contacts the test tray in a second position for testing the IC devices in a second line in the test tray. The test tray is then transferred to the discharge area. Another aspect of the automatic handler is provided with a groove on the test tray to increase a number of test position for the test tray. The groove includes an end surface which engages with the positioning stoppers.